

Search Notes**Application/Control No.**

10/603,520

Examiner

Chau Nguyen

Applicant(s)/Patent under Reexamination

CHRISTIAN ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	501.1	12/6/2005	CN
715	513	12/6/2005	CN
715	536	12/6/2005	CN
715	540	12/6/2005	CN
709	200	12/6/2005	CN
709	217	12/6/2005	CN
707	104.1	12/06/2005	CN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	12/06/2005	CN
	12/07/2005	CN
	12/8/2005	CN
NPL Search on IEEE Database	12/8/2005	CN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner